

## N-Channel 40-V (D-S) MOSFET

### PRODUCT SUMMARY

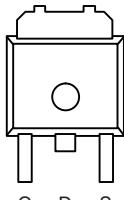
$V_{DS}$ (V)	$R_{DS(on)}$ ( $\Omega$ )	$I_D$ (A) <sup>a</sup>	$Q_g$ (Typ.)
40	0.0088 at $V_{GS} = 10$ V	50	16 nC
	0.0105 at $V_{GS} = 4.5$ V	50	

### FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % UIS Tested
- 100 %  $R_g$  Tested
- PWM Optimized
- Compliant to RoHS Directive 2002/95/EC



TO-252

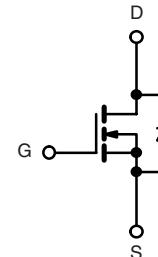


Drain Connected to Tab

Top View

### APPLICATIONS

- LCD Display Backlight Inverters
- DC/DC Converters



Ordering Information: SUD50N04-8m8P-4GE3 (Lead (Pb)-free and Halogen-free)

N-Channel MOSFET

### ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current ( $T_J = 150$ °C)	$I_D$	50 <sup>a</sup>	A
		44	
		14 <sup>b</sup>	
		11.2 <sup>b</sup>	
Pulsed Drain Current	$I_{DM}$	100	
Continuous Source-Drain Diode Current	$I_S$	40	
		2.6 <sup>b</sup>	
Single Pulse Avalanche Current	$I_{AS}$	30	
Avalanche Energy	$E_{AS}$	45	mJ
Maximum Power Dissipation	$P_D$	48.1	W
		30.8	
		3.1 <sup>b</sup>	
		2.0 <sup>b</sup>	
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to 150	°C

### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b</sup>	$R_{thJA}$	32	40	°C/W
Maximum Junction-to-Case	$R_{thJC}$	2.1	2.6	

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

**SPECIFICATIONS**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

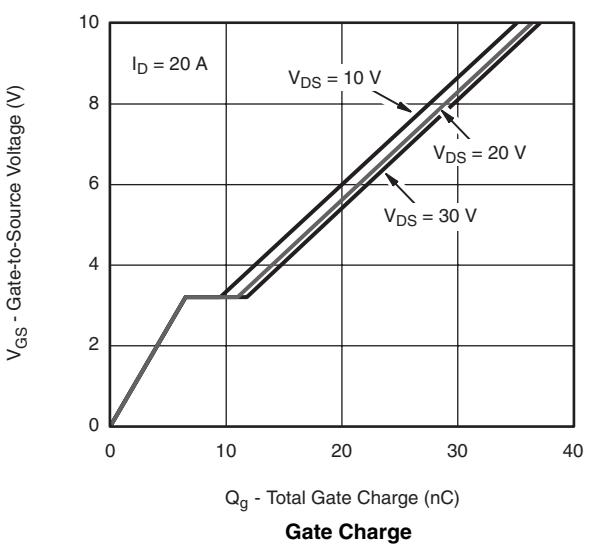
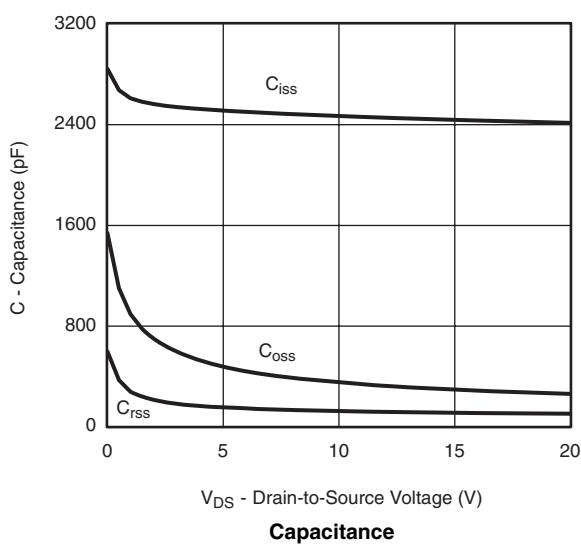
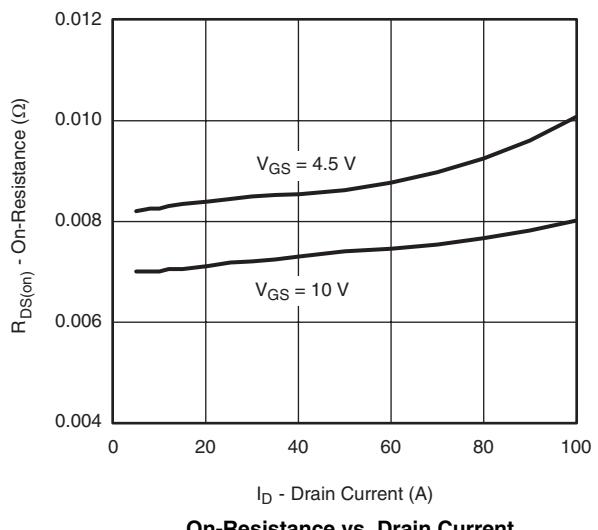
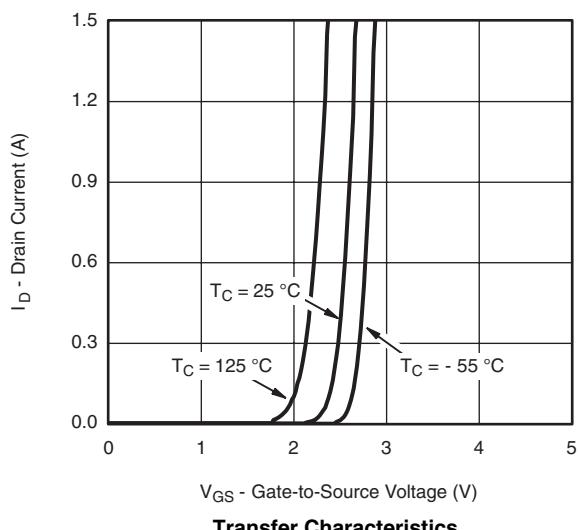
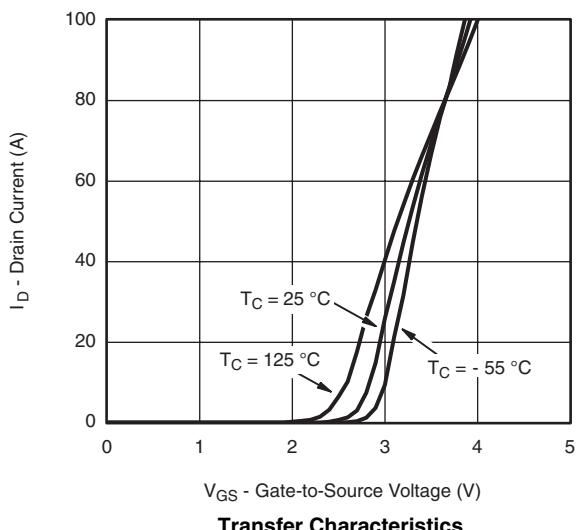
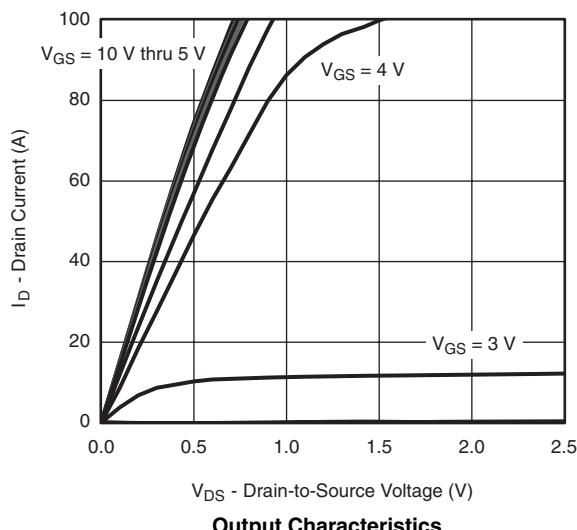
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V	
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 1.0 \text{ mA}$		44		mV/ $^\circ\text{C}$	
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 5.9			
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.5		3.0	V	
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			$\pm 100$	nA	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		1		$\mu\text{A}$	
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 70^\circ\text{C}$			20		
On-State Drain Current <sup>a</sup>	$I_{D(\text{on})}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			A	
Drain-Source On-State Resistance <sup>a</sup>	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0069	0.0088	$\Omega$	
		$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$		0.0084	0.0105		
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 15 \text{ A}$		75		S	
<b>Dynamic<sup>b</sup></b>							
Input Capacitance	$C_{iss}$	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		2400		pF	
Output Capacitance	$C_{oss}$			260			
Reverse Transfer Capacitance	$C_{rss}$			100			
Total Gate Charge	$Q_g$	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		37	56	nC	
Gate-Source Charge	$Q_{gs}$			16	24		
Gate-Drain Charge	$Q_{gd}$	$V_{DS} = 20 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		6.5			
Gate Resistance	$R_g$			4.5			
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 20 \text{ V}, R_L = 1 \Omega$ $I_D \approx 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		2.5	5.5	8.5	$\Omega$
Rise Time	$t_r$				30	45	ns
Turn-Off Delay Time	$t_{d(\text{off})}$				15	25	
Fall Time	$t_f$				45	70	
Turn-On Delay Time	$t_{d(\text{on})}$				15	25	
Rise Time	$t_r$				9	15	
Turn-Off Delay Time	$t_{d(\text{off})}$				5	10	
Fall Time	$t_f$				40	60	
					5	10	
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_S$	$T_C = 25^\circ\text{C}$			40	A	
Pulse Diode Forward Current <sup>a</sup>	$I_{SM}$				100		
Body Diode Voltage	$V_{SD}$	$I_S = 10 \text{ A}$		0.81	1.2	V	
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = 20 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		22	35	ns	
Body Diode Reverse Recovery Charge	$Q_{rr}$			14	25	nC	
Reverse Recovery Fall Time	$t_a$			11		ns	
Reverse Recovery Rise Time	$t_b$			11			

Notes:

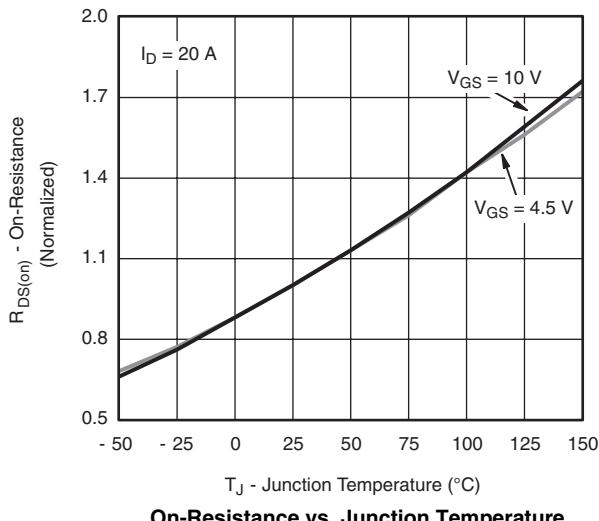
a. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .

b. Guaranteed by design, not subject to production testing.

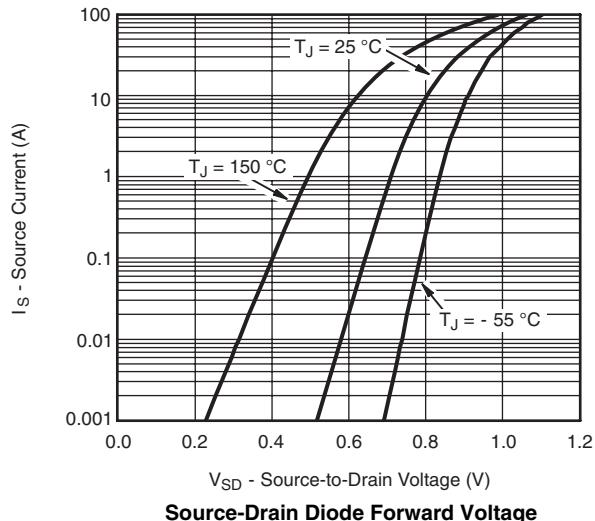
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted


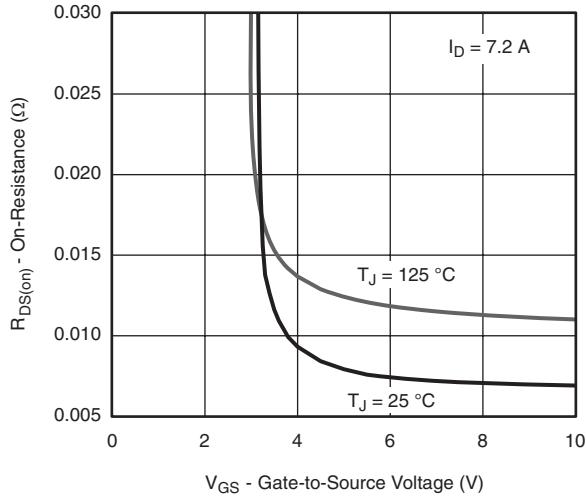
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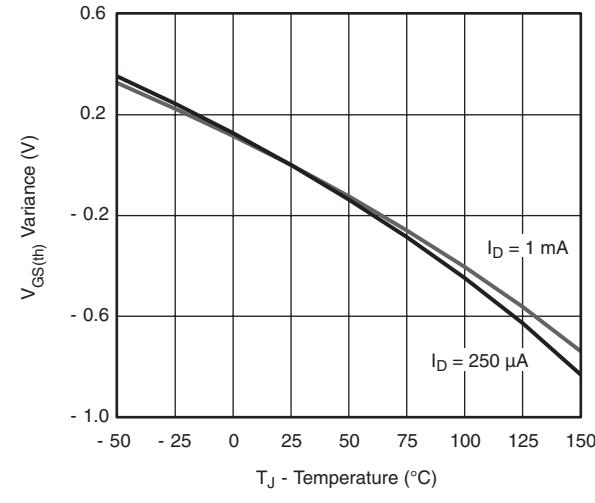
On-Resistance vs. Junction Temperature



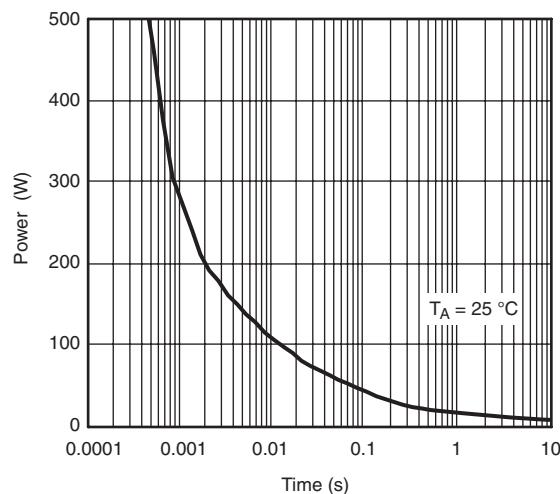
Source-Drain Diode Forward Voltage



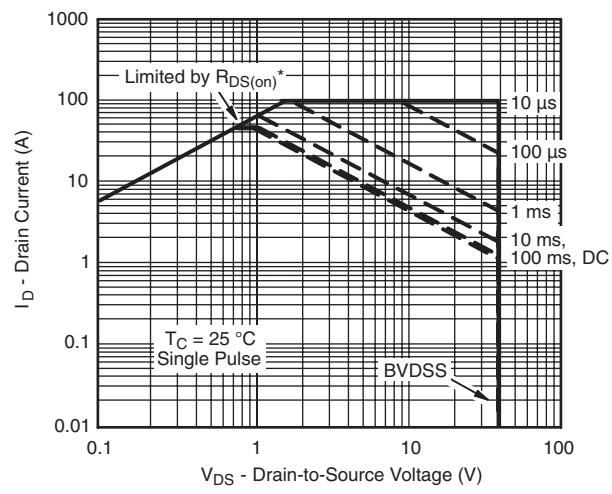
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

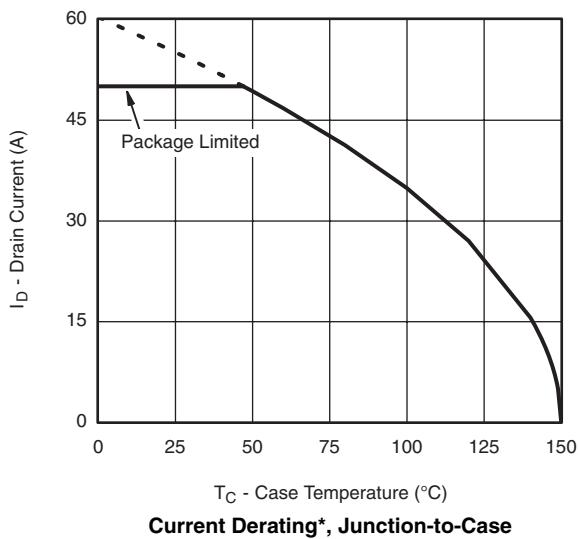
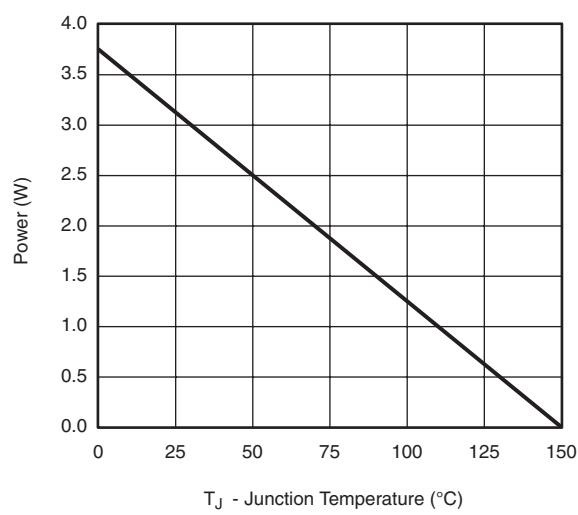
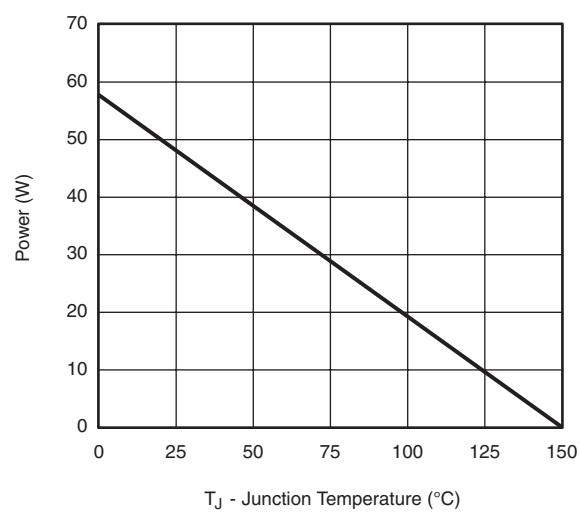


Single Pulse, Junction-to-Ambient



\*  $V_{GS} >$  minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Case

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

**Current Derating\*, Junction-to-Case**

**Power Derating, Junction-to-Ambient**

**Power Derating, Junction-to-Case**

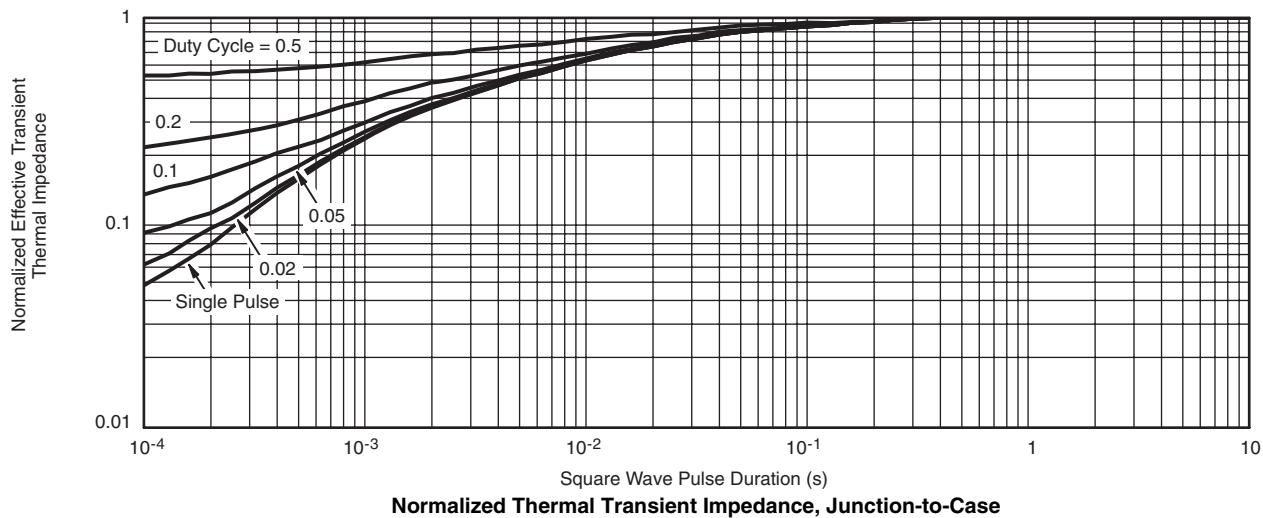
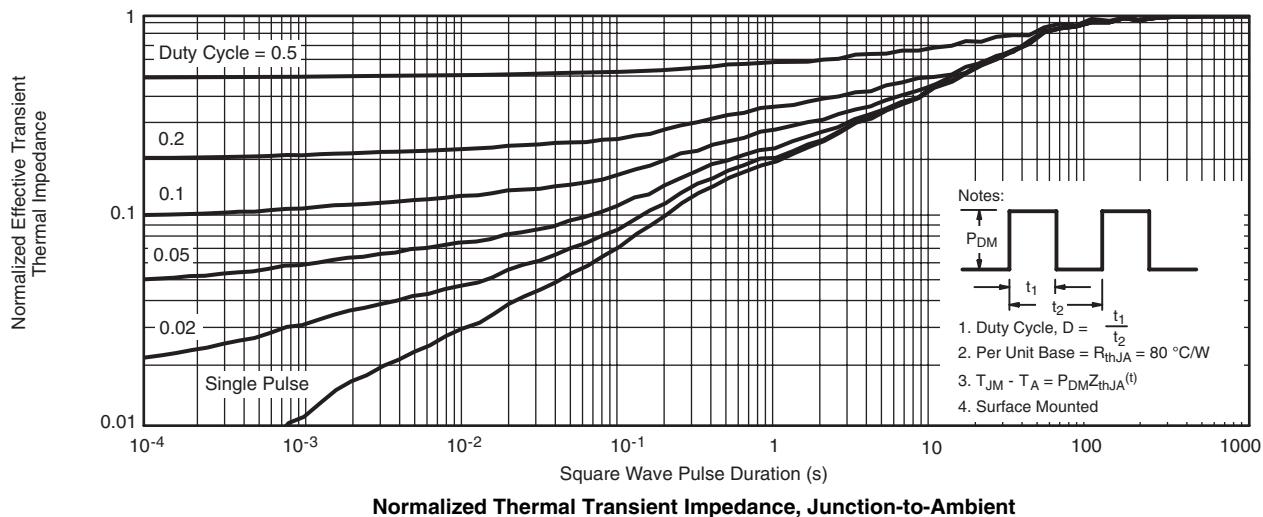
\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

# SUD50N04-8m8P

Vishay Siliconix



**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted



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